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YV	AA	5 190 981	03/02/93	William J. WECHTER						
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		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO				
YV	AO	54-154724	12/06/79	JP(equivalent of GB 1596033)			NO			
YV	AP	96/23759	08/08/96	WO(with partial Engish translation)			NO			
YV	AQ	8-319252	12/03/96	JP(with partial English translation)			NO			
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